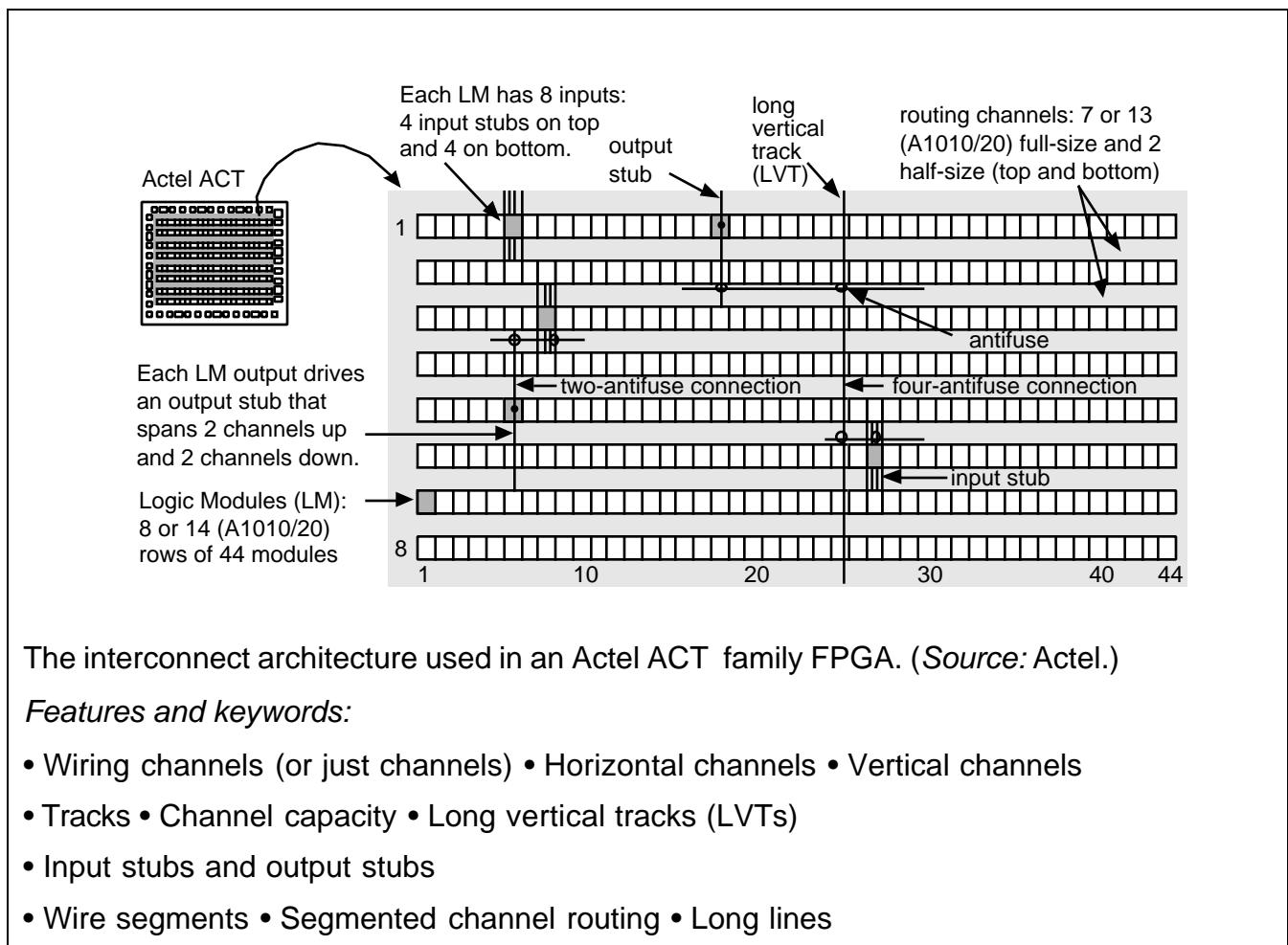


PROGRAMMABLE ASIC INTERCONNECT

7

Key concepts: programmable interconnect • raw materials: aluminum-based metallization and a line capacitance of 0.2pFcm^{-1}

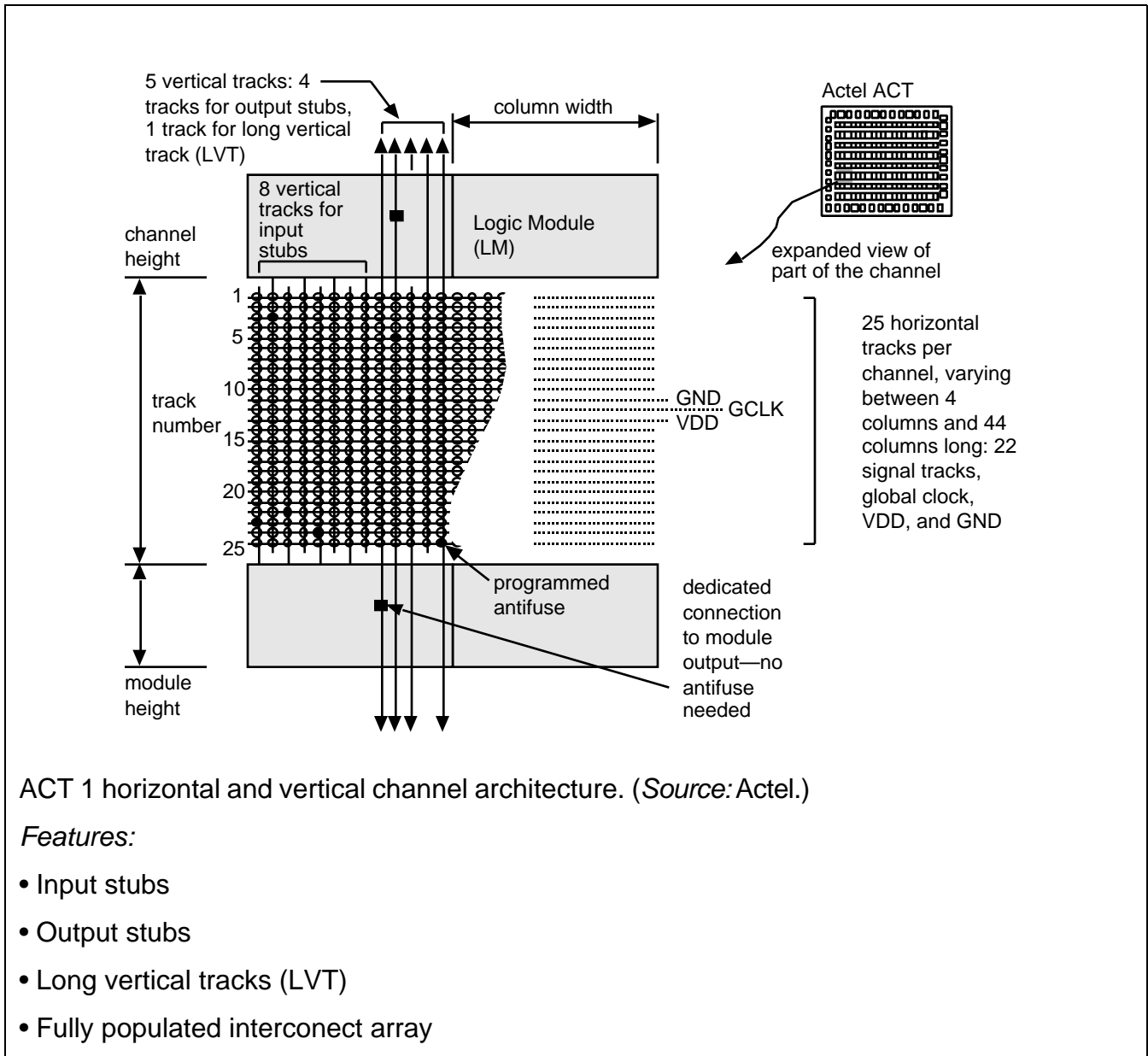
7.1 Actel ACT



The interconnect architecture used in an Actel ACT family FPGA. (Source: Actel.)

Features and keywords:

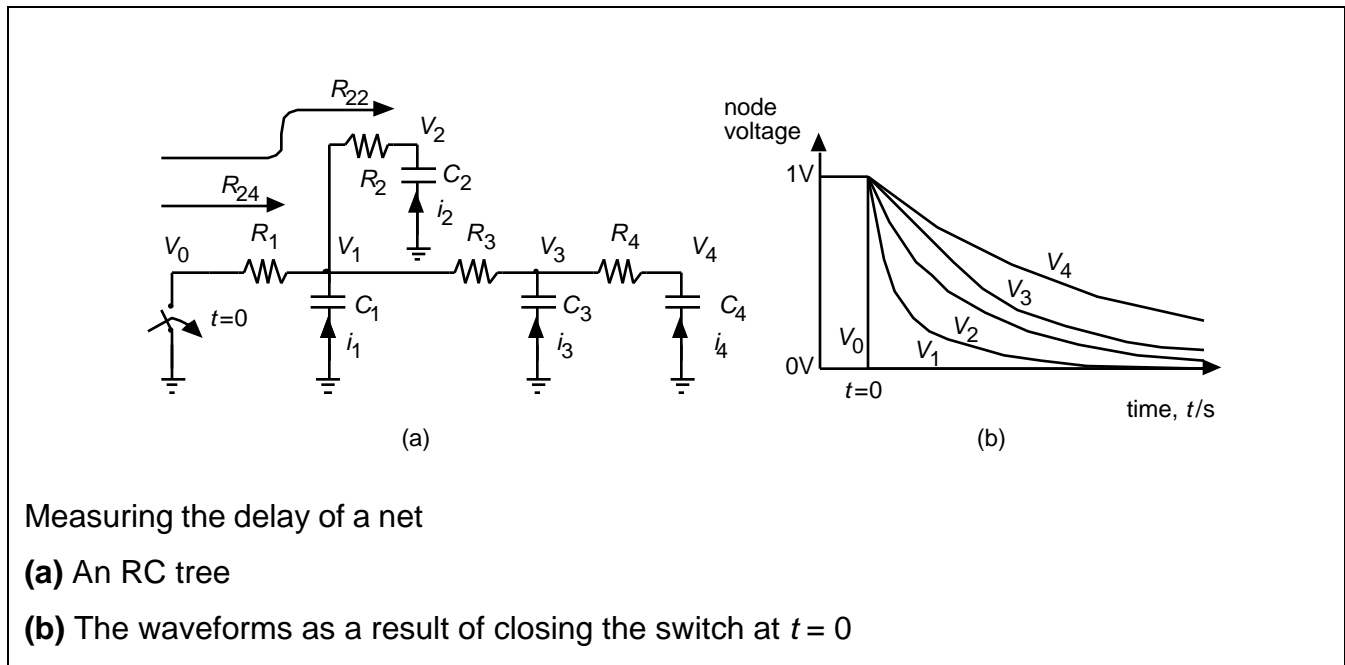
- Wiring channels (or just channels) • Horizontal channels • Vertical channels
- Tracks • Channel capacity • Long vertical tracks (LVTs)
- Input stubs and output stubs
- Wire segments • Segmented channel routing • Long lines



7.1.1 Routing Resources

Actel FPGA routing resources						
	Horizontal tracks per channel, H	Vertical tracks per column, V	Rows, R	Columns, C	Total antifuses on each chip	H×V×R × C
A1010	22	13	8	44	112,000	100,672
A1020	22	13	14	44	186,000	176,176
A1225A	36	15	13	46	250,000	322,920
A1240A	36	15	14	62	400,000	468,720
A1280A	36	15	18	82	750,000	797,040

7.1.2 Elmore's Constant

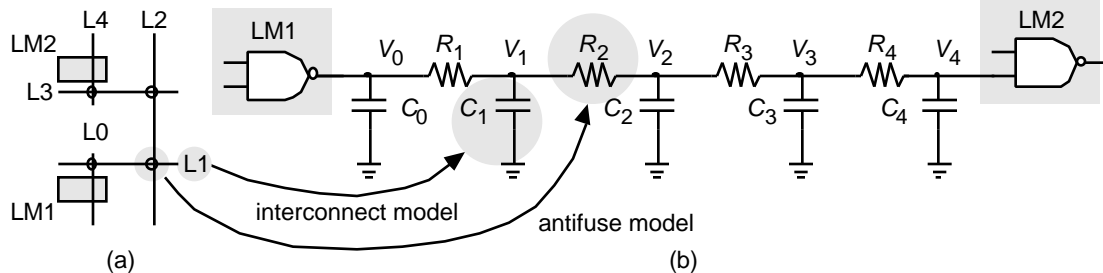


$$V_j(t) = \exp(-t/D_j) ; \quad D_j = \sum_{k=1}^n R_{ki}C_k$$

The time constant D_j is often called the **Elmore delay** and is different for each node.

I call D_j the **Elmore time constant** as a reminder that, if we approximate V_j by an exponential waveform, the delay of the RC tree using 0.35/0.65 trip points is approximately D_j seconds.

7.1.3 RC Delay in Antifuse Connections



Actel routing model

(a) A four-antifuse connection. L0 is an output stub, L1 and L3 are horizontal tracks, L2 is a long vertical track (LVT), and L4 is an input stub

(b) An RC-tree model. Each antifuse is modeled by a resistance and each interconnect segment is modeled by a capacitance.

$$D_4 = R_{14}C_1 + R_{24}C_2 + R_{14}C_1 + R_{44}C_4$$

$$= (R_1 + R_2 + R_3 + R_4)C_4 + (R_1 + R_2 + R_3)C_3 + (R_1 + R_2)C_2 + R_1C_1$$

$$D_4 = 4RC_4 + 3RC_3 + 2RC_2 + RC_1$$

- Two antifuses will generate a $3RC$ time constant
- Three antifuses a $6RC$ time constant
- Four antifuses gives a $10RC$ time constant
- Interconnect delay grows quadratically (n^2) as we increase the interconnect length and the number of antifuses, n

7.1.4 Antifuse Parasitic Capacitance

7.1.5 ACT 2 and ACT 3 Interconnect channel density • fast fuse

Actel interconnect parameters		
Parameter	A1010/A1020	A1010B/A1020B
Technology	2.0 μ m, =1.0 μ m	1.2 μ m, =0.6 μ m
Die height (A1010)	240mil	144mil
Die width (A1010)	360mil	216mil
Die area (A1010)	86,400mil ² =56M ²	31,104mil ² =56M ²
Logic Module (LM) height (Y1)	180 μ m=180	108 μ m=180
LM width (X)	150 μ m=150	90 μ m=150
LM area (X \times Y1)	27,000 μ m ² =27k ²	9,720 μ m ² =27k ²
Channel height (Y2)	25 tracks=287 μ m	25 tracks=170 μ m
Channel area per LM (X \times Y2)	43,050 μ m ² =43k ²	15,300 μ m ² =43k ²
LM and routing area (X \times Y1+X \times Y2)	70,000 μ m ² =70k ²	25,000 μ m ² =70k ²
Antifuse capacitance	—	10 fF
Metal capacitance	0.2pFmm ⁻¹	0.2pFmm ⁻¹
Output stub length (spans 3 LMs + 4 channels)	4 channels=1688 μ m	4 channels=1012 μ m
Output stub metal capacitance	0.34pF	0.20pF
Output stub antifuse connections	100	100
Output stub antifuse capacitance	—	1.0pF
Horiz. track length	4–44 cols.= 600–6600 μ m	4–44 cols.= 360–3960 μ m
Horiz. track metal capacitance	0.1–1.3pF	0.07–0.8pF
Horiz. track antifuse connections	52–572 antifuses	52–572 antifuses
Horiz. track antifuse capacitance	—	0.52–5.72 pF
Long vertical track (LVT)	8–14 channels=3760–6580 μ m	8–14 channels=2240–3920 μ m
LVT metal capacitance	0.08–0.13pF	0.45–0.8pF
LVT track antifuse connections	200–350 antifuses	200–350 antifuses
LVT track antifuse capacitance		2–3.5pF
Antifuse resistance (ACT 1)		0.5k (typ.), 0.7k (max.)

Actel interconnect:

An input stub (1 channel) connects to 25 antifuses

An output stub (4 channels) connects to 100 (25×4) antifuses

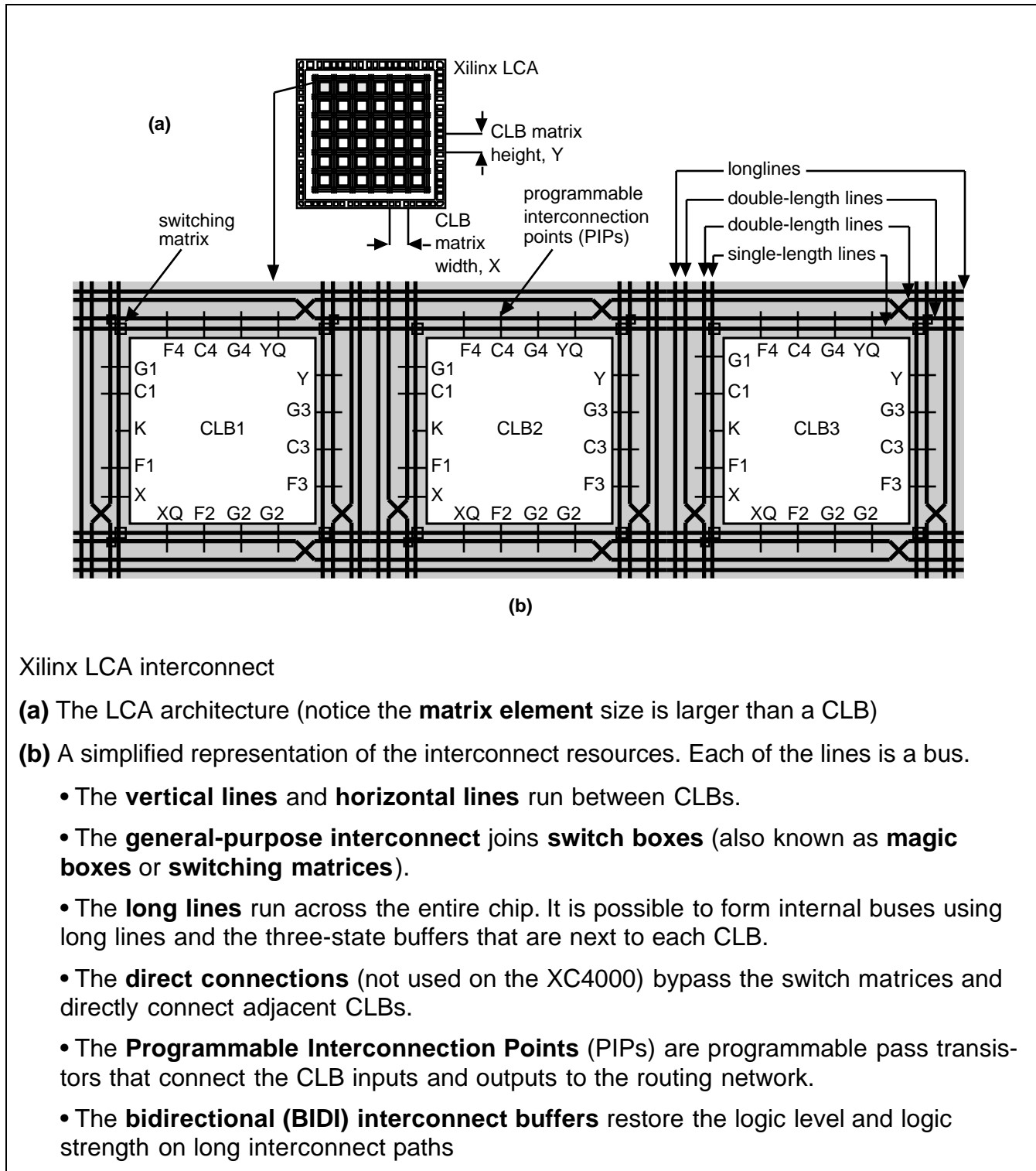
An LVT (1010, 8 channels) connects to 200 (25×8) antifuses

An LVT (1020, 14 channels) connects to 350 (25×14) antifuses

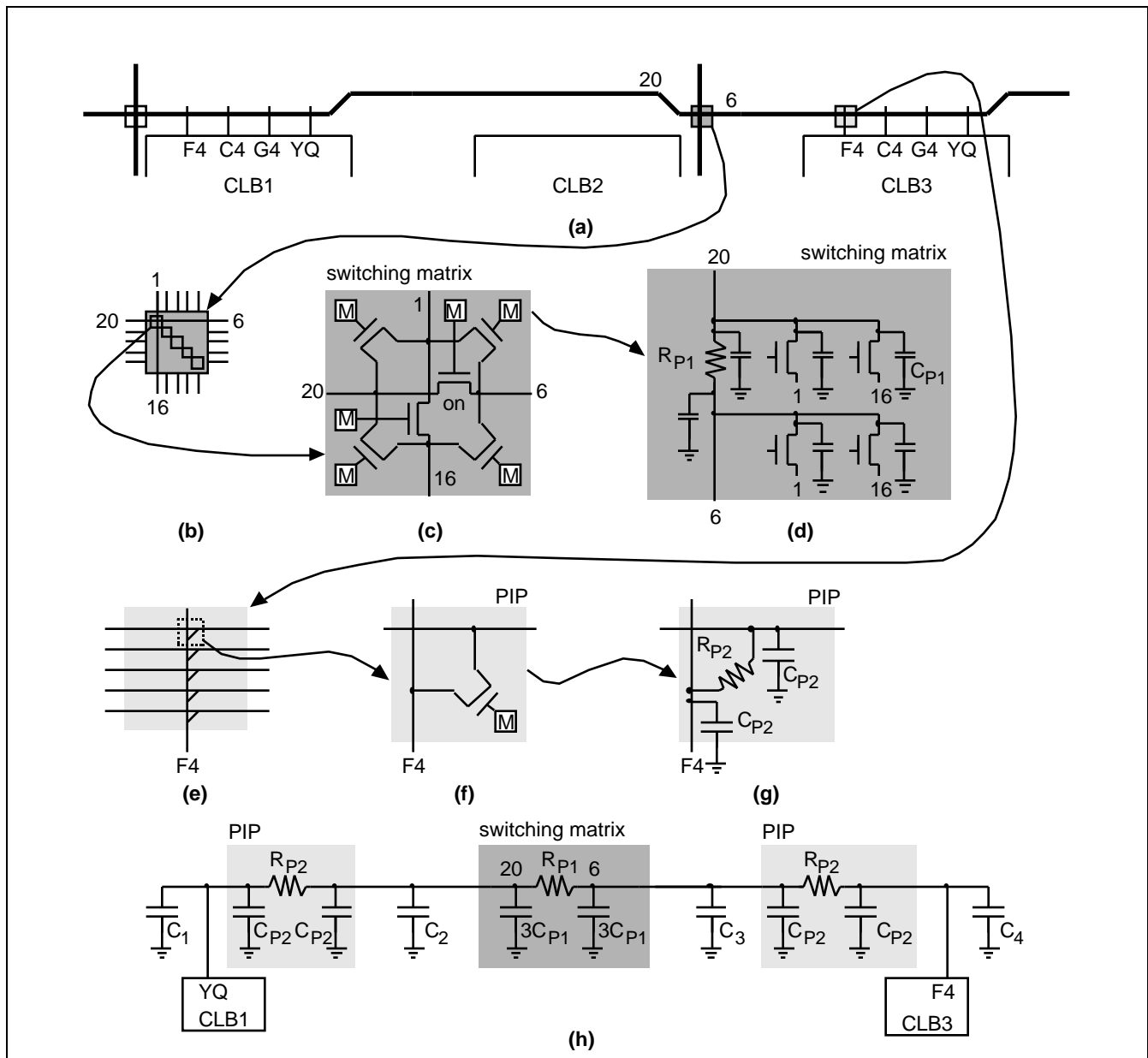
A four-column horizontal track connects to 52 (13×4) antifuses

A 44-column horizontal track connects to 572 (13×44) antifuses

7.2 Xilinx LCA



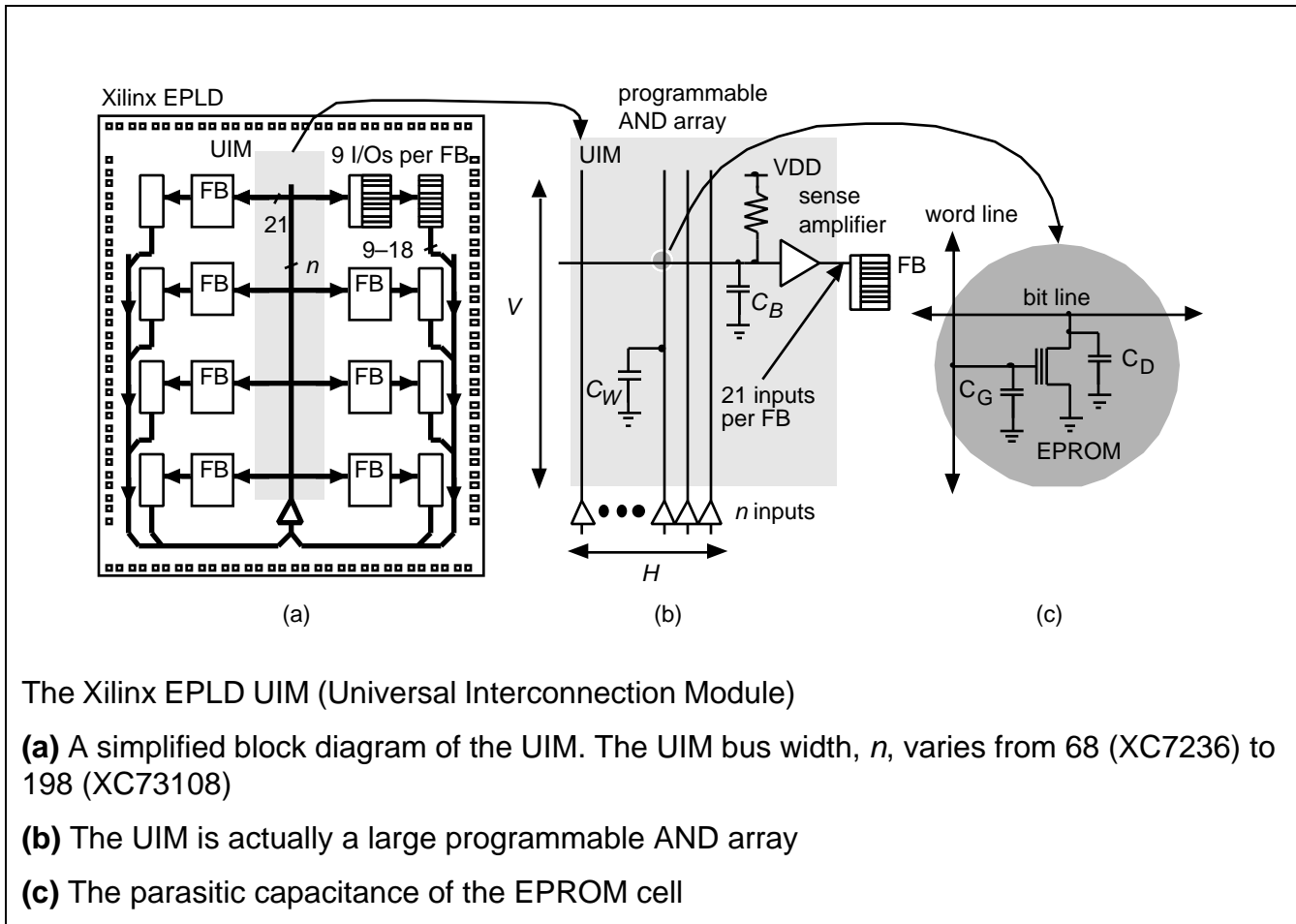
XC3000 interconnect parameters	
Parameter	XC3020
Technology	1.0 μm , =0.5 μm
Die height	220mil
Die width	180mil
Die area	39,600mil ² =102M ²
CLB matrix height (Y)	480 μm =960
CLB matrix width (X)	370 μm =740
CLB matrix area (X \times Y)	17,600 μm^2 =710k ²
Matrix transistor resistance, R _{P1}	0.5–1k
Matrix transistor parasitic capacitance, C _{P1}	0.01–0.02pF
PIP transistor resistance, R _{P2}	0.5–1k
PIP transistor parasitic capacitance, C _{P2}	0.01–0.02pF
Single-length line (X, Y)	370 μm , 480 μm
Single-length line capacitance: C _{LX} , C _{LY}	0.075pF, 0.1pF
Horizontal Longline (8X)	8 cols.=2960 μm
Horizontal Longline metal capacitance, C _{LL}	0.6pF



Components of interconnect delay in a Xilinx LCA array

- (a) A portion of the interconnect around the CLBs
- (b) A switching matrix
- (c) A detailed view inside the switching matrix showing the pass-transistor arrangement
- (d) The equivalent circuit for the connection between nets 6 and 20 using the matrix
- (e) A view of the interconnect at a Programmable Interconnection Point (PIP)
- (f) and (g) The equivalent schematic of a PIP connection
- (h) The complete RC delay path

7.3 Xilinx EPLD



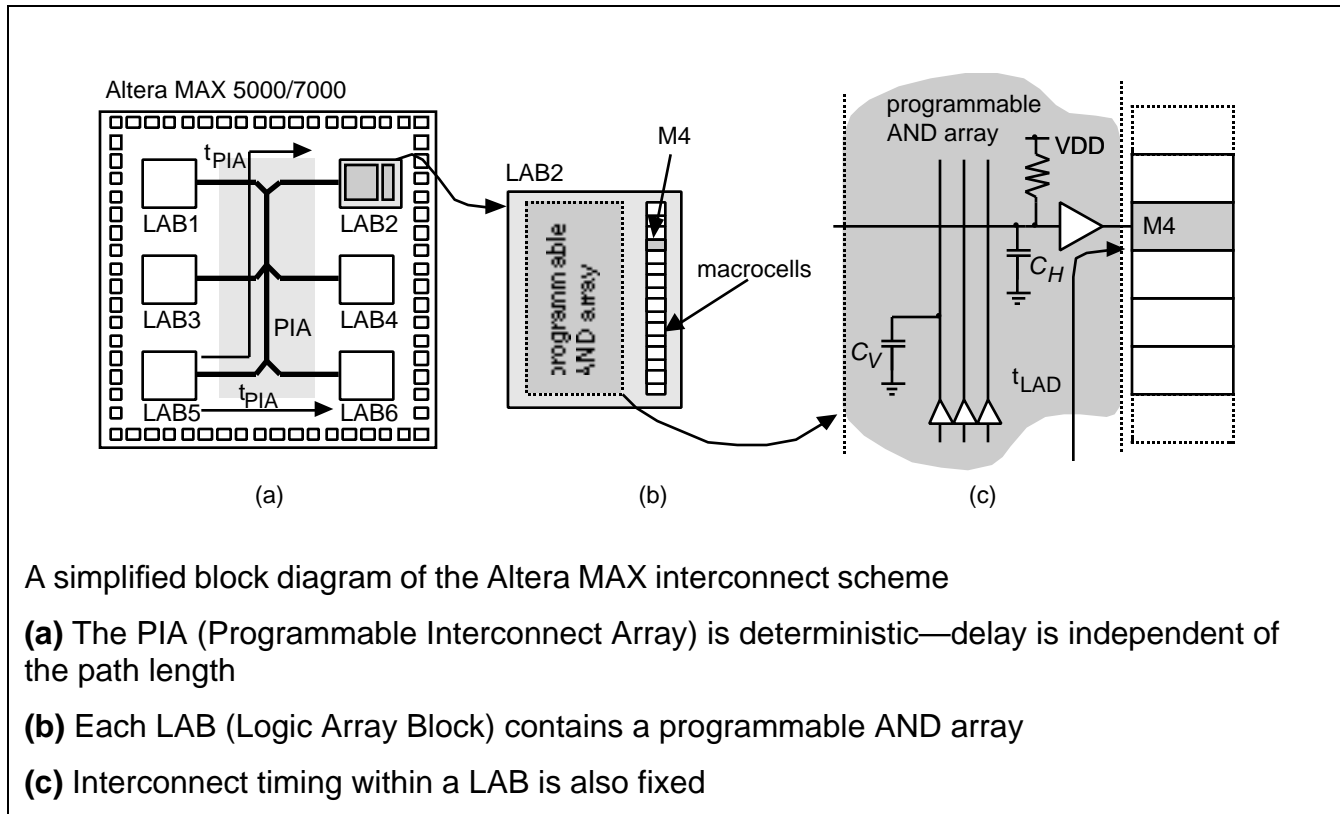
The Xilinx EPLD UIM (Universal Interconnection Module)

(a) A simplified block diagram of the UIM. The UIM bus width, n , varies from 68 (XC7236) to 198 (XC73108)

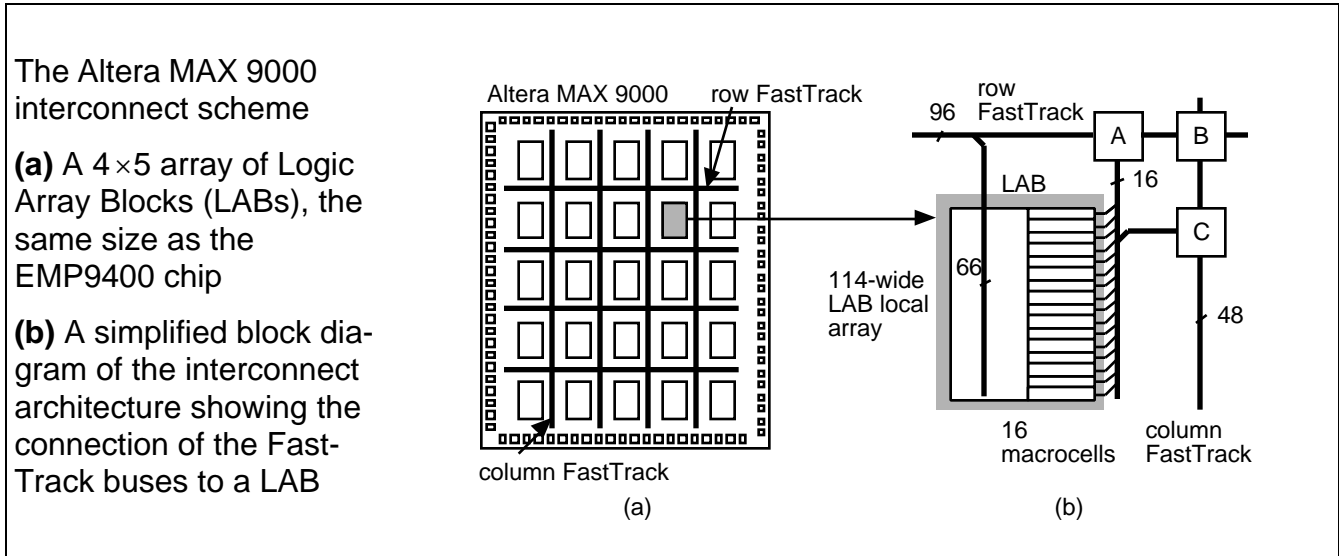
(b) The UIM is actually a large programmable AND array

(c) The parasitic capacitance of the EPROM cell

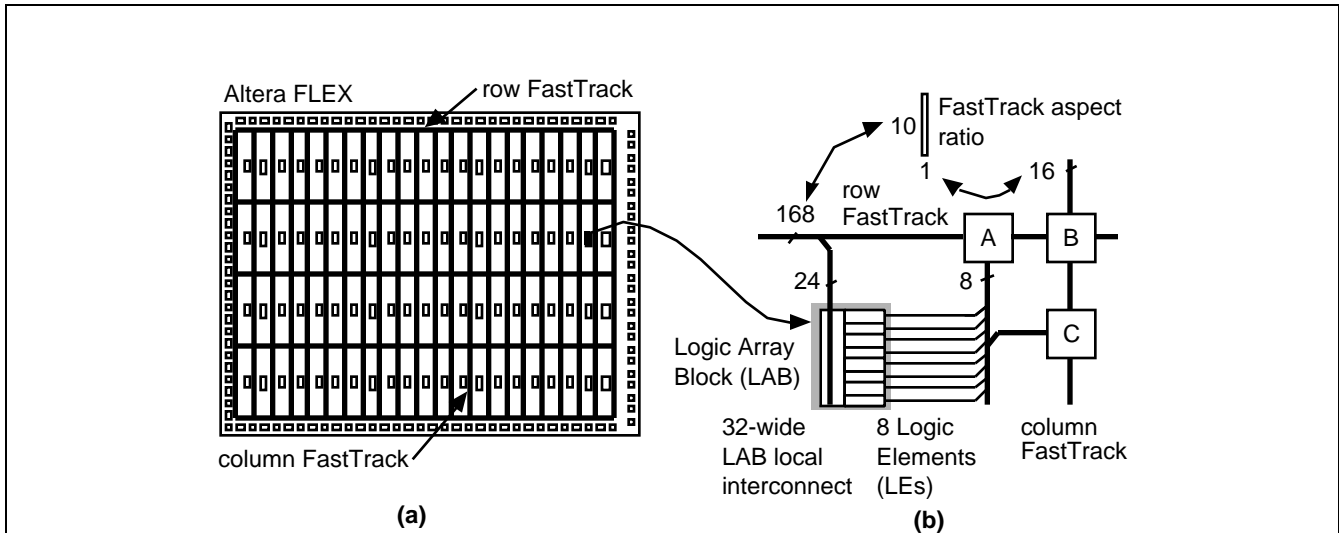
7.4 Altera MAX 5000 and 7000



7.5 Altera MAX 9000



7.6 Altera FLEX



The Altera FLEX interconnect scheme

(a) The row and column FastTrack interconnect. The chip shown, with 4 rows x 21 columns, is the same size as the EPF8820

(b) A simplified diagram of the interconnect architecture showing the connections between the FastTrack buses and a LAB. Boxes A, B, and C represent the bus-to-bus connections

7.7 Summary

The RC product of the parasitic elements of an antifuse and a pass transistor are not too different. However, an SRAM cell is much larger than an antifuse which leads to coarser interconnect architectures for SRAM-based programmable ASICs. The EPROM device lends itself to large wired-logic structures.

These differences in programming technology lead to different architectures:

- The antifuse FPGA architectures are dense and regular.
- The SRAM architectures contain nested structures of interconnect resources.
- The complex PLD architectures use long interconnect lines but achieve deterministic routing.

Key points:

- The difference between deterministic and nondeterministic interconnect
- Estimating interconnect delay
- Elmore's constant

7.8 Problems

